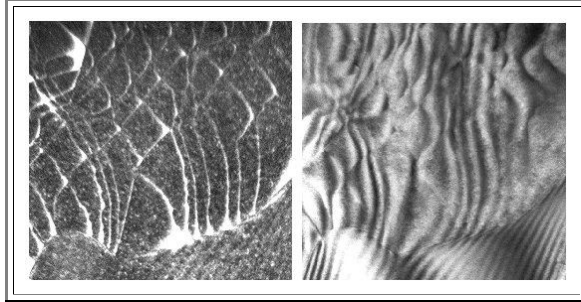


Comparison of Weak-Beam and Bright Field Conditions

The two pictures below show the extremes in resolution.

- On the left hand side is a weak beam image of a dislocation network in a small angle grain boundary in **Si**; it has optimum resolution. The dislocation end at a **SiO₂** precipitate which shows faint fringes due to Moirée effects (the **Si** precipitate is sandwiched between **Si** crystals which are slightly misoriented).
- On the right hand side is the same area imaged with (rather dynamical) bright field conditions. The dislocation lines are very broad and their images interfere with each other; it would be difficult to interpret this picture.



Illustration